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## **INFORMATION DISCLOSURE** STATEMENT BY APPLICANT

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Complete if Known			
Application Number	09/735,983-Conf. #5697		
Filing Date	December 13, 2000		
First Named Inventor	Seth Haberman		
Art Unit	2611		
Examiner Name	H. V. Tran		
Attomey Docket Number	2000522.00123US2		

	U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No.1	Document Number  Number-Kind Code <sup>2</sup> ( # known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	
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Examiner Signature	/Hai Tran/ (04/02/2007)	Date Considered	
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	•			Application Number	09/735,983-Conf. #5697
<b>INFORMATION DISCLOSURE</b>			SCLOSURE	Filing Date	December 13, 2000
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	(Use as many sheets as necessary)			Art Unit	2611
				Examiner Name	H. V. Tran
Sheet	2	of	2	Attorney Docket Number	2000522.00123US2

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